



EMC Analysis in Wireless Communication

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Message from the Guest Editors

The EMC problems of 5G systems are exacerbated by the presence of complex high-frequency, multifunctional, digital circuits and numerous wireless devices deployed throughout the propagation channel. Not only the EMC tests need to evaluate emission and immunity, but also identify the key sources of EMC failures. Due to the complexity of 5G systems, the analysis and identification of EMC failure sources are particularly intricate and challenging. Therefore, new test solutions and post-processing techniques are needed to address the challenges of 5G EMC tests, also assessing the coexistence constraints with existing fixed and mobile installations.

This Special Issue will report on new advancements in EMC analysis in wireless communication that include, but are not limited to, the following topics:

- RC theory and characterization
- Emission
- Immunity
- Coexistence
- Channel modelling
- Field statistics
- Wave chaos
- Antennas
- MIMO/massive MIMO
- Reconfigurable intelligent surfaces
- Software defined radio





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Message from the Editor-in-Chief

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